



Stefan Spießberger (Autor)
**Compact Semiconductor-Based Laser Sources with Narrow
Linewidth and High Output Power**



Leibniz
Ferdinand-Braun-Institut

24

Forschungsberichte aus dem
Ferdinand-Braun-Institut
Leibniz-Institut
für Höchstfrequenztechnik

Innovationen mit Mikrowellen & Licht

Compact Semiconductor-Based Laser
Sources with Narrow Linewidth and
High Output Power



Stefan Spießberger

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Telefon: +49 (0)551 54724-0, E-Mail: info@cuvillier.de, Website: <https://cuvillier.de>



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